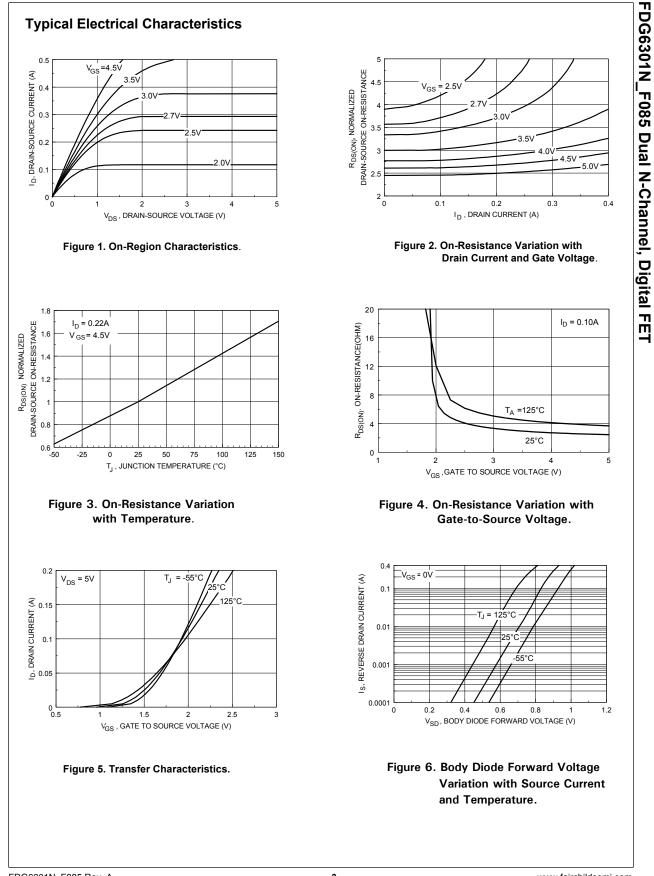
SEM		N	larch 2009		
FDG	6301N_F085				
	N-Channel, Digital FET				
These field ef proprie very h	ral Description dual N-Channel logic level enhancement mode ffect transistors are produced using Fairchild's stary, high cell density, DMOS technology. This igh density process is especially tailored to ze on-state resistance. This device has been	 Features 25 V, 0.22 A continuous, 0.65 A peak. R_{DS(ON)} = 4 Ω @ V_{GS} = 4.5 V, R_{DS(ON)} = 5 Ω @ V_{GS} = 2.7 V. Very low level gate drive requirements allowing direct 			
design replace	ed especially for low voltage applications as a ement for bipolar digital transistors and small	 operation in 3 V circuits (V_{GS(th)} < 1.5 V). Gate-Source Zener for ESD ruggedness 			
signal	MOSFETs.	(>6kV Human Body Model).	(>6kV Human Body Model).		
		 Compact industry standard SC70-6 surface r package. 	nount		
OOT		Qualified to AEC Q101	Qualified to AEC Q101		
	40,	 RoHS Compliant 			
(,				
SC7	0-6 SOT-23 SuperSOT [™] -6	SuperSOT [™] -8 SO-8	SOT-223		
	D1 G1 D2 G1 D2 S1 S1 S1 S1 S1 S1 S1 S1 S1 S1	2 or 5 3 or 6 3 or 6			
Units in	outs are symmetrical; pin 1 and 4 are interchangeable. side the carrier can be of either orientation and will not affect th ute Maximum Ratings $T_A = 25^{\circ}C$ unless oth		_		
Symbol	Parameter	FDG6301N_F085	Units		
V _{DSS}	Drain-Source Voltage	25	V		
V _{GSS}	Gate-Source Voltage	8	V		
	Drain/Output Current - Continuous	0.22	Α		
l _D	- Pulsed Maximum Power Dissipation (Note 1)	0.65	W		
	(NOLE 1)		°C		
P _D	Operating and Storage Temperature Range	6.0 KV			
	Operating and Storage Temperature Range Electrostatic Discharge Rating MIL-STD-883D Human Body Model(100 pF / 1500 Ω)	6.0	kV		
P _D T _J ,T _{STG} ESD	Electrostatic Discharge Rating MIL-STD-883D	6.0	kV		

Symbol	Parameter	Conditions		Min	Тур	Max	Units
OFF CHAR	ACTERISTICS			•			
BV _{DSS}	Drain-Source Breakdown Voltage	$V_{GS} = 0 V, I_{D} = 250 \mu A$		25			V
$\Delta BV_{DSS}/\Delta T_{J}$	Breakdown Voltage Temp. Coefficient	I_{D} = 250 µA, Referenced to	o 25°C		25		mV /°C
I _{DSS}	Zero Gate Voltage Drain Current	V _{DS} = 20 V, V _{GS} = 0 V				1	μA
			T _J = 55°C			10	μA
I _{GSS}	Gate - Body Leakage Current	$V_{GS} = 8 V, V_{DS} = 0 V$				100	nA
ON CHARAG	CTERISTICS (Note 2)			•			
V _{GS(th)}	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$		0.65	0.85	1.5	V
$\Delta V_{GS(th)} / \Delta T_J$	Gate Threshold Voltage Temp.Coefficient	$I_{\rm D}$ = 250 µA, Referenced to	o 25°C		-2.1		mV /°C
R _{DS(ON)}	Static Drain-Source On-Resistance	$V_{GS} = 4.5 \text{ V}, I_{D} = 0.22 \text{ A}$			2.6	4	Ω
			T _J =125°C		5.3	7	
		$V_{GS} = 2.7 \text{ V}, I_{D} = 0.19 \text{ A}$			3.7	5	
I _{D(ON)}	On-State Drain Current	$V_{GS} = 4.5 V, V_{DS} = 5 V$		0.22			Α
9 _{FS}	Forward Transconductance	$V_{\rm DS} = 5 \text{ V}, \ \text{I}_{\rm D} = 0.22 \text{ A}$			0.2		S
DYNAMIC C	HARACTERISTICS						
C _{iss}	Input Capacitance	$V_{DS} = 10 \text{ V}, V_{GS} = 0 \text{ V},$ f = 1.0 MHz			9.5		pF
C _{oss}	Output Capacitance				6		pF
C _{rss}	Reverse Transfer Capacitance				1.3		pF
SWITCHING	CHARACTERISTICS (Note 2)			-	-		
t _{D(on)}	Turn - On Delay Time	$V_{DD} = 5 V, I_{D} = 0.5 A,$ $V_{GS} = 4.5 V, R_{GEN} = 50 \Omega$			5	10	ns
ţ	Turn - On Rise Time				4.5	10	ns
t _{D(off)}	Turn - Off Delay Time				4	8	ns
t,	Turn - Off Fall Time				3.2	7	ns
Q _g	Total Gate Charge	$V_{DS} = 5 V, I_D = 0.22 A,$ $V_{GS} = 4.5 V$	$V_{DS} = 5 V, I_{D} = 0.22 A,$		0.29	0.4	nC
Q _{gs}	Gate-Source Charge	$V_{GS} = 4.5 V$			0.12		nC
Q _{gd}	Gate-Drain Charge				0.03		nC
DRAIN-SOU	RCE DIODE CHARACTERISTICS AND MAXIM	IUM RATINGS					
l _s	Maximum Continuous Source Current					0.25	A
V _{SD}	Drain-Source Diode Forward Voltage	$V_{GS} = 0 V, I_{S} = 0.25 A$ (Note	e 2)		0.8	1.2	V

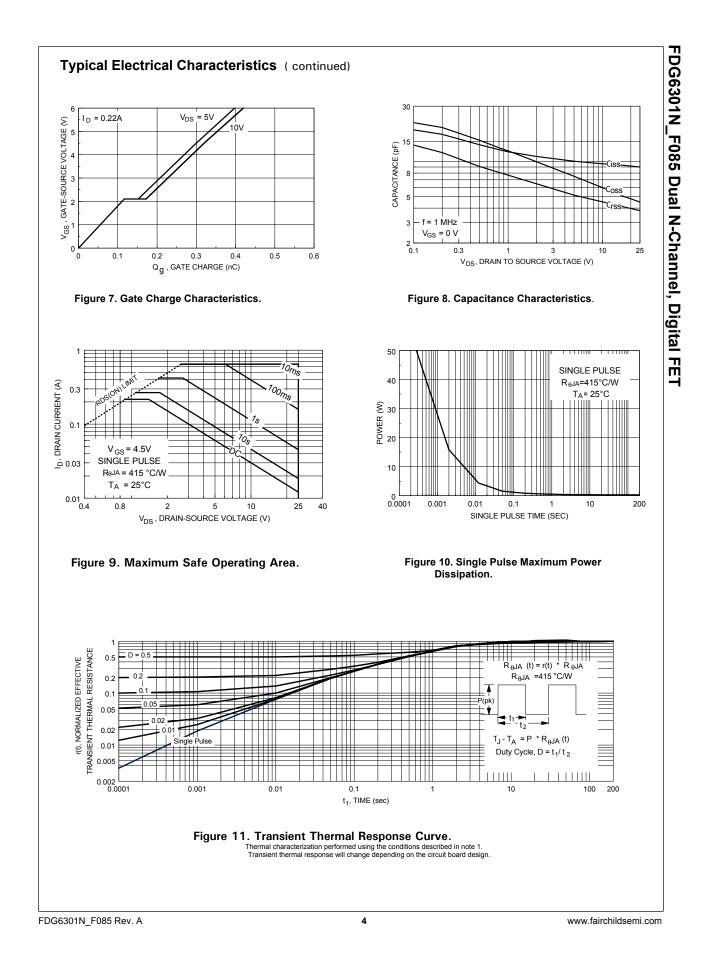
FDG6301N_F085 Dual N-Channel, Digital FET

1. R_{pik} is the sum of the junction-to-case and case-to-ambient thermal resistance where the case thermal reference is defined as the solder mounting surface of the drain pins. R_{pik} is guaranteed by design while $R_{y_{0}h}$ is determined by the use's board design. $R_{y_{0}h} = 415^{\circ}$ C/W on minimum pad mounting on FR-4 board in still air. 2. Pulse Test: Pulse Width \leq 300µs, Duty Cycle \leq 2.0%.

FDG6301N_F085 Rev. A



FDG6301N_F085 Rev. A





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Obsolete	Not In Production	Datasheet contains specifications on a product that is discontinued by Fairchild Semiconductor. The datasheet is for reference information only.
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